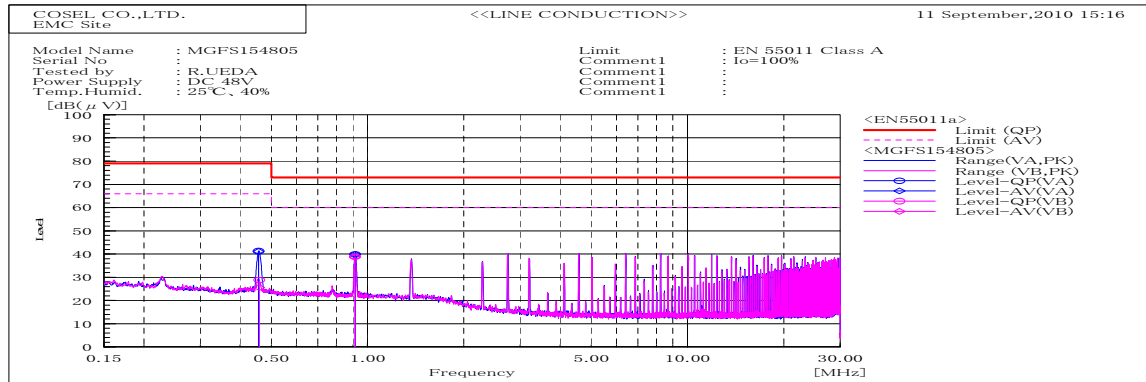
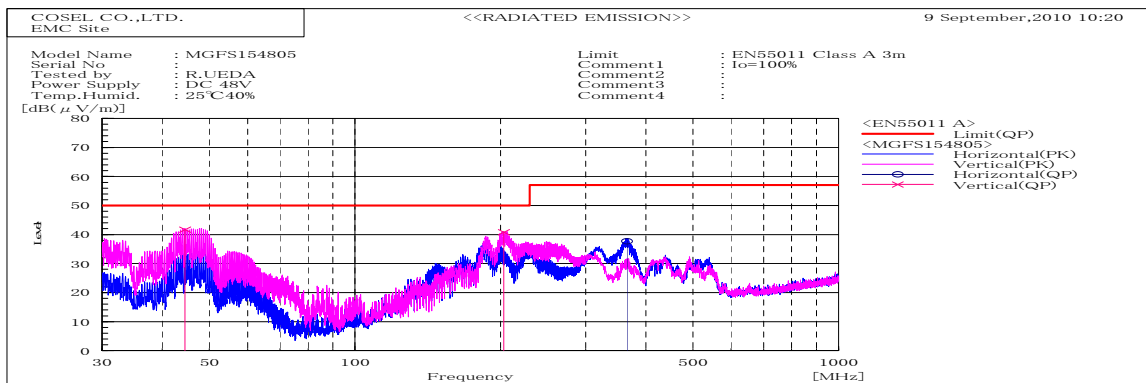


DATA SHEET		Date	21-Sep-10
Model	MGFS154805	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	R.Ueda



Frequency MHz	Harm	Line Phase	Reading dB(uV)		Factor dB	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.45635		VA	31.1	31	10.1	41.2	41.1	79	66	37.8	24.9	Pass	
0.45868		VB	18.8	15.6	10	28.8	25.6	79	66	50.2	40.4	Pass	
0.91311		VB	28.9	28.7	10	38.9	38.7	73	60	34.1	21.3	Pass	
0.91495		VA	29.8	29.7	10.1	39.9	39.8	73	60	33.1	20.2	Pass	



Frequency MHz	Polarization	Stability	Reading dB(uV)		Space Loss dB	Level dB(mW)		Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	AV						
44.544	V	Stable	62.7		-21	41.7		50	8.3	Pass	103	0	
203.298	V	Stable	62.7		-21.9	40.8		50	9.2	Pass	115	241	
365.289	H	Stable	53.5		-15.8	37.7		57	19.3	Pass	106	192	

DATA SHEET

Model	Circuit used for measurement
Test	EMI Line conduction & Radiated emission

1. Line conduction



2. Radiated emission

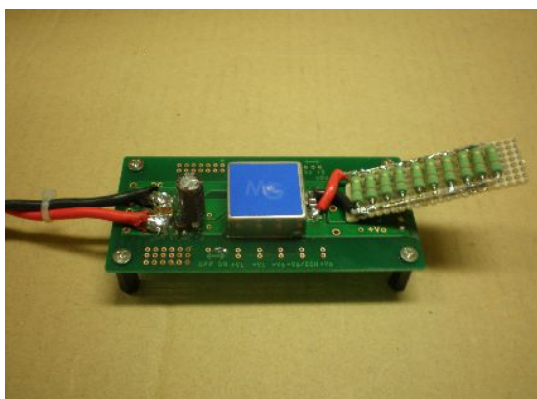


Conditions

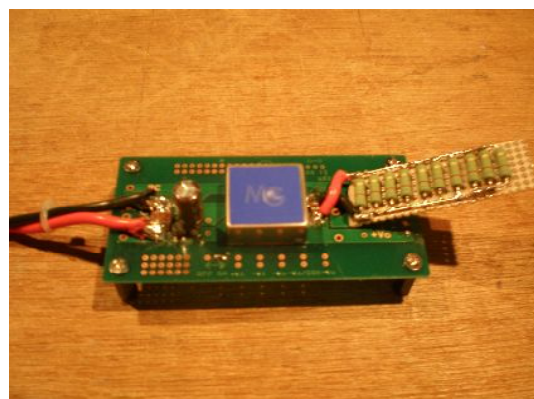
Test : EMI
Model Name : MGFS1548□□/MGFW1548□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

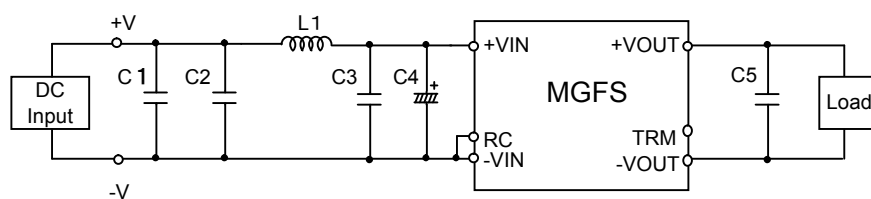


Fig.1 Testing circuitry 1

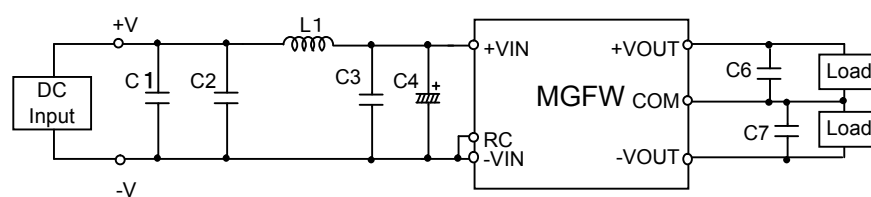


Fig.2 Testing circuitry 2

L1	: 10 μ H	CI4C-100	(KORIN ELECTRONICS)
C1,C2,C3	: 100V	2.2 μ F C4532JB2A225MT	(TDK)
C4	: 80V	47 μ F LXV80VB47M	(NIPPON CHEMI-CON)
C5,C6,C7	: 25V	22 μ F CM32X5R226K25A	(KYOCERA)